Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	69	(CMOS complementary metal oxide semisf conductor complementary symmetry metal oxide semisf conductor) AND transient AND time AND integral AND current AND power supply AND analy§4 AND ("10" OR integrated circuit) AND ("713".clas. OR "726".clas. R"380".clas. "326".clas. "714".clas. AND ("0pd<"20040217" or @ad<"20040217" or @ad<"20040217" or @prad<"20040217" or @grad<"20040217" or @grad<"200402	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 10:17
L3	58	(test pattern test criteri\$2) AND (points data sets measurements) AND transient AND current AND power supply AND analy\$4 AND ("10" OR integrated circuit) AND ("713".das. OR "726".das. OR "380".das. "324".das. "326".das. "714".das.) AND (@dd< "20040217" or @prad< "20040217" or @dad< "20040217" or @flad< "20040217" or @flad	US-PGPUB; USPAT; USCOR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 10:35
L4	85	(test pattern test criteri\$2 test set) AND (points data sets measurements) AND transient AND current AND power supply AND analy\$4 AND ("10" OR integrated circuit) AND ("713" clas. OR "726".clas. OR "380".clas. "324".clas. "326".clas. "314".clas.) AND (@pd-"20040217" or @ad<"20040217" or @prad<"20040217" or @idad<"20040217" or @idad	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 11:06
L5	26	abnormal\$3 AND (test pattern test criteri\$2 test set) AND (points data sets measurements) AND transient AND current AND power supply AND analy\$4 AND ("10" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas. "714".clas. AND ("Qpd< "20040217" or @ad< "20040217" or @ad< "20040217" or @prad< "20040217" or @riad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 11:07
L6	56	fault\$3 AND (test pattern test criteri\$2 test set) AND (points data sets masurements) AND transient AND current AND power supply AND analy\$4 AND ("IC" OR integrated circuit) AND ("713". das. OR "726". das. OR "380". das. "324". das. "326". das. "714". das.) AND ("porad-"20040217" or @ad<"20040217" or @prad-"20040217" or @prad-"20040217" or @riad<"20040217" or % "20040217"	US-PGPUB; USPAT; USCOR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 11:08

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L7	23	fault\$3 AND abnormal\$3 AND (test pattern test criteri\$2 test set) AND (points data sets measurements) AND transient AND current AND power supply AND analy\$4 AND ("IC" OR integrated circuit) AND ("13".clas. OR "726".das. OR "380".clas. "324".das. "326".das. "714".das.) AND (@pdc. "20040217" or @prad< "20040217" or @grad< "20040217" or @grad< "20040217" or @flad< "20040217" or @flad	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 11:08
L8	23	fault\$3 AND abnormal\$3 AND (test pattern test criteri\$2 test set) AND (points data sets measurements) AND transient AND current AND power supply AND analy\$4 AND ("1C" O'R integrated circuit) AND ("13" clas. O'R "26" clas. OR "380" clas. "324" clas. "326" clas. "714" clas. "324" clas. AND (@pd="20040217" or @ad="20040217" or @prad<"20040217" or @flad="20040217" or @flad="20040217".	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 11:13
L9	8	"5943346".pn. "5505539".pn. "5864566".pn. "4646299".pn.	US-PGPUB; USPAT; USOOR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 11:16
S1	109	defect AND ("1C" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713" das. OR "726" das. OR "380". das.) AND (@pdc "20000404" or @ad<"20000404" or @prad<"20000404" or @itade "20000404"	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:48
82	63	analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713" das. OR "726" (das. OR "380" das.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @plad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:49
\$3	0	transient power supply AND analysis AND defect AND ("10" O'R integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".das. OR "726".das. OR "380".das.) AND ("974" 20000404" or @ad-2"20000404" or @prad<"20000404" or @grad<"20000404" or	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:50
S4	51	power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".das. OR "380".clas.) AND (@pd<"20000404" or @ad< "20000404" or @prad< "20000404" or @itad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 17:00

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S5	40	fault AND power supply AND analysis AND defect AND ("IC" O'R integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".das. OR "726".das. OR "380".das.) AND ("0;dd="200000404" or @ad="200000404" or @irad<"200000404" or @irad<"20000404"	US-PGPUB; USPAT; USOOR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51
S6	40	current AND fault AND power supply AND analysis AND defect AND ("10" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713" clas. OR "726". clas. OR "380". clas.) AND ("Qpd <"20000404" or "@ad<"20000404 or "@ad<"20000404" or @prad<"20000404" or @riad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:50
S7	37	potential AND current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated direuit) AND (semiconductor OR semi-conductor) AND ("713" das. O "726" das. O "380" das.) AND (@pdc "20000404" or @prad<"20000404" or @prad<"20000404	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51
\$8	9	voltage AND current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND ("pd-"20000404" or @pd-"20000404" or @prad-"20000404" or @prad-"20000404" or @prad-"20000404")	US-PGPUB; USPAT; USOOR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51
S9	9	current AND voltage AND current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713" clas. OR "726" clas. OR "380" clas.) AND (@gdc."20000404" or @adc."20000404" or @idad-"20000404"	US-PGPUB; USPAT; USCOR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51
S10	2	*6043672".pn.	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/22 09:34
S11	11	current AND voltage AND current AND fault AND power supply AND analysis AND defects 3 AND ("IC OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("718" class OR "726" class OR "380" clas) AND ("718" class OR "2000404" or @pad<-"20000404" or @prad<-"20000404" or @prad	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 14:56

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S12	27	current AND voltage AND fault AND defect\$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713" das. OR "726" das. OR "380". das.) AND (@pd "20000404" or @ad< "20000404" or @prad< "20000404" or @ilad "20000404" or @ilad "20000404" or @ilad "20000404".	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 14:57
S13	11	fault location AND ("713".clas. OR "726". das. OR "380".das. AND (@pd. "20000404" or @ad. "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:23
S14	14	(fault location defect\$3 signal\$1) AND ("713" clas. OR "726" clas. OR "380" clas.) AND (@pd-="20000040" or @prad< "20000404" or @prad< "200004" or @prad<	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:23
S15	5	(("IC" OR integrated circuit) (semiconductor OR semi-conductor)) AND (fault location) [defect\$3 signal\$1) AND ("713".das. OR "726".das. OR "380".das.) AND (@pd<"20000404" or @prad<"20000404" or @prad<"20000404" or @fad<"20000404" or @fad<"	US-PGPUB; USPAT; USOOR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:34
S16	189433	(ishida.in. yamaguchi.in. hashimoto.in.)	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:35
S17	36	(ishida.in. yamaguchi.in. hashimoto.in.) AND Tault AND defect\$3 AND analysis AND ("IC" integrated circuit semi\$1 conductor)	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:36
S18	205	(("IC" OR integrated circuit) (semiconductor OR semi-conductor)) AND (fault location defect\$3 signal\$1) AND ("713".das. OR "726".das. OR "380".das. "324".das.) AND (@pd-"20000404" or @ad-"20000404" or @prad<"20000404" or @rlad<"2000404"	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:41
S19	698	(fault location defect\$3 signal\$1) AND ("713" das. OR "786" das. OR "880" das. 324" das.) AND (@pd-2'20000404" or @ad<"20000404" or @prad<"20000404" or @lad<"20000404" or @lad<"20000404" or @lad<"20000404" or @lad<"2	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:41

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\$20	278	current AND voltage AND fault AND defedt\$3 AND ("IC" OR integrated dircuit) AND (semiconductor OR semi-conductor) AND ("713" das. OR "726" das. OR "380" das. "1"324" das.) AND (@pd<"20000404" or @ad<"20000404" or @rlad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:41
S21	77	current AND voltage AND current AND fault AND power supply AND analysis AND defects AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713" class OR "726" class OR "380" clas "324" class) AND (@pd<"20000404" or @qrad<"20000404" or @qrad<"20000404" or @qrad<"20000404" or @riad<"20000404" or	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:42
\$22	8	signal\$1 AND fault AND current AND voltage AND (fault location defect\$3 signal\$1) AND power supply AND analysis AND defect\$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713" das. OR "726" das. OR "380" das. "324" das.) AND (@pd<"20000404" or @prad<"20000404" or @prad<"20000404" or @riad<"20000404"	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:43
\$23	8	signal\$1 AND fault\$1 AND current AND voltage AND (fault location defect\$3 signal\$1) AND power supply AND analysis AND defect\$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713" das. OR "726" das. OR "380" das. OR "324" das.) AND (@pd< "20000404" or @prad< "20000404" or @prad< "20000404" or @rad< "2000404" or @r	US-PGPUB; USPAT; USOOR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:43
\$24	26	(ishida.in. yamaguchi.in. hashimoto.in.) AND fault AND defect\$3 AND analysis AND ("C" integrated circuit) AND (semi\$1 conductor)	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:48
\$25	66	(stor\$3 memory medium media) AND current AND voltage AND current AND fault AND power supply AND analysis AND defect\$3 AND ("IC" OR integrated circuit) AND (semiconductor OFI semi-conductor) AND ("713" das. OR "726" das. OR "380" das. "1"344" das.) AND (@pd-"20000404" or @ade."20000404" or @plad-"20000404" or @ralad-"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:59

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S26	2	"6043672".pn.	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 16:40
S27	64	transient AND voltage AND current AND fault AND power supply AND analysis AND defects AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713" clas. OR "726" clas. OR "380" clas. "324" clas. OR "30" clas. "324" clas. OR "30" clas. "324" clas. OR "20"	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/01/08 15:32
S28	20	transient current AND voltage AND current AND fault AND power supply AND analysis AND defects AND ("10" CM integrated circuit) AND (semiconductor CR semi-conductor) AND ("713" clas. OR "726" clas. OR "380" clas. "324" clas.) AND (@pd< "20040217" or @prad< "20040217" or @grad< "20040217" or @flad< "20	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/01/08 15:49
S29	6	transient current AND time AND integral AND voltage AND current AND fault AND power supply AND analysis AND defects AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713" clas. OR "726" clas. OR "380" clas. "324" clas. AND (@pd-"20040217" or @ad<"20040217" or @prad<"20040217" or @prad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/01/08 15:49
S30	13	transient current AND time AND integral AND voltage AND current AND (fault defect\$3, AND power supply AND analy\$4 AND ("IC" OR integrated circuit) AND ("713" clas. Of "256" clas. OR "380" clas. "324" clas.) AND (@pd="20040217" or @prad="20040217" or @prad="20040	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:11
S31	8	(CMOS complementary metal oxide semiconductor) AND transient current AND time AND integral AND voltage AND current AND (fault defect\$3) AND power supply AND analy\$4 AND (1°C OR integrated circuit) AND ("713" clas. OR "726" clas. OR "380" clas. "324" clas.) AND (@pd<"20040217" or @ad<"20040217" or @grad<"20040217" or @	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:12

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S32	8	(CMOS complementary metal oxide semisl conductor complementary symmetry metal oxide semisl conductor) AND transient current AND time AND integral AND voltage AND current AND (flault defect\$3) AND power supply AND analy\$4 AND ("10" OR integrated circuit) AND ("10" class. OR "726" class. OR "30" class ("380" class OR "30" class OR "20" class OR "	US-PGPUB; USPAT; USOCR; EPO; DEFIMENT; IBM_TDB	ADJ	ON	2009/06/18 17:12
\$33	6	(CMOS complementary metal oxide semist conductor complementary symmetry metal oxide semist conductor) AND transient AND time AND (sum NEAR integral) AND current AND power supply AND analys4 AND ("C" OR integrated circuit) AND ("713" clas. OR "726" clas. OR "380" clas. "324" clas.) AND ("Qpd< "20040217" or @ad< "20040217" or @prad< "20040217" or @riad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:15
\$34	6	transient AND time AND (sum NEAR integral) AND current AND power supply AND analy\$4 AND ("1C" OR integrated dirouit) AND ("713" clas. OR "726" clas. OR "380" clas. "324" clas.) AND ("6pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @prad<"20040217" or @prad<"20040217" or @riad<"20040217")	US-PGPUB; USPAT; USOOR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:16
\$35	6	transient AND time AND (sum NEAR integral) AND current AND power supply AND analyst AND ("C OR integrated circuit) AND ("713" clas. OR "726" clas. OR "380" clas.] AND ("924" clas.] AND ("924" clas.] ("924" clas.	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:16
S36	7	transient AND time AND (sum NEAR integral) AND current AND power supply AND analys4 AND ("10" OR integrated circuit) AND ("718" das. OR "728" odas. OR "880" das. "324" das. "328" das. "374" das.) AND (@0d-"20040217" or @ad<"20040217" or @prad<"20040217" or @lad<"20040217")	US-PGPUB; USPAT; USCOR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:16
S37	256	transient AND time AND (sum total talley) AND integral AND current AND power supply AND analysk AND ("C" OR integrated circuit) AND ("713".das. OR "726".das. OR "380".das. "324".das. "326".das. "714".das.) AND (@pd<*20040217" or @ad<*20040217" or @ad<*20040217" or @prad<*20040217" or @ridad<*20040217" or gridad<*20040217" or gridad<*	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:17

\$38	56	(CMOS complementary metal oxide semis1 conductor complementary symmetry metal oxide semis1 conductor) AND transient AND time AND (sum total talley) AND integral AND current AND power supply AND analy\$4 AND ("1C" OR integrated circuit) AND ("713".das. OR "726".das. OR "380".das. "324".das. "326".das. "714".das.) AND ("Qpd < "20040217" or @ad < "20040217" or @prad < "20040217" or @grad	US-PGPUB; USPAT; USOCR; EPO; DEFWENT; IBM_TDB	ADJ	ON	2009/06/18 17:17
S39	10	(CMOS complementary metal oxide semist conductor complementary symmetry metal oxide semist conductor) AND transient AND time AND (sum total talley) AND (time NEAR integral) AND current AND power supply AND analys*4 AND ("IC" OR integrated circuit) AND ("713" class. OR "726" class. OR "380" class. "324" class. "326" class. "714" clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @griad<"20040217"	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:17
S40	10	(CMOS complementary metal oxide semisf conductor complementary symmetry metal oxide semisf conductor) AND transient AND tim53 AND (sum total talley) AND (time NEAR integral) AND current AND power supply AND analy\$4 AND (*1C* OR integrated circuit) AND (*713" clas. OR "726" clas. OR "380" clas. "326" clas. "714" clas.) AND (@pd < "20040217" or @ad < "20040217" or @prad < "20040217" or @prad < "20040217" or @plad	US-PGPUB; USPAT; USOCR; EPO; DEFEWENT; IBM_TDB	ADJ	ON	2009/06/18 17:18